

# IGBT Modules

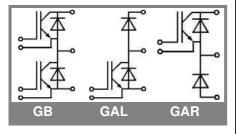
SKM 200GB173D SKM 200GB173D1 SKM 200GAL173D SKM 200GAR173D

#### **Features**

- MOS input (voltage controlled)
- N channel , Homogeneous Si
- · Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 x I<sub>cnom</sub>
- · Latch-up free
- Fast & soft inverse CAL diodes
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (13 mm) and creepage distance (20 mm)

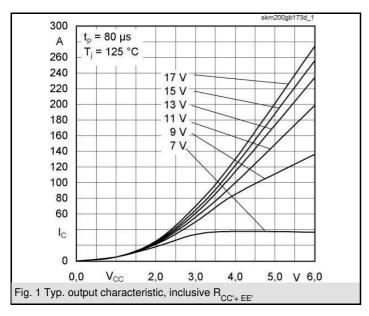
#### **Typical Applications**

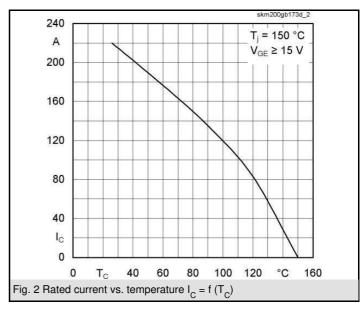
- AC inverter drives on mains 575 -750 V<sub>AC</sub>
- DC bus voltage 750 1200 V<sub>DC</sub>
- Public transport (auxiliary syst.)
- Switching (not for linear use)

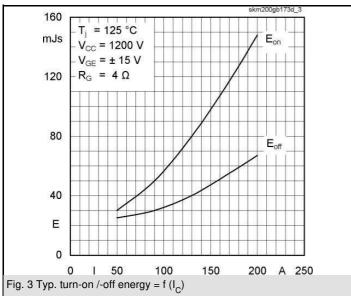


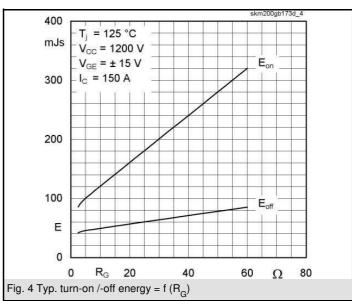
<b>Absolute Maximum Ratings</b> $T_c = 25  ^{\circ}\text{C}$ , unless otherwise specified								
Symbol	Conditions	Values	Units					
IGBT								
$V_{CES}$		1700	V					
I <sub>C</sub>	$T_c = 25 (80)  ^{\circ}C$	220 (150)	Α					
I <sub>CRM</sub>	$t_p = 1 \text{ ms}$	300	Α					
$V_{GES}$		± 20	V					
$T_{vj}$ , $(T_{stg})$	$T_{OPERATION} \leq T_{stg}$	- 40 <b>+</b> 150 (125)	°C					
V <sub>isol</sub>	AC, 1 min.	4000	V					
Inverse diode								
I <sub>F</sub>	T <sub>c</sub> = 25 (80) °C	150 (100)	Α					
I <sub>FRM</sub>	t <sub>p</sub> = 1 ms	300	Α					
I <sub>FSM</sub>	$t_p = 10 \text{ ms; sin.; } T_j = 150 ^{\circ}\text{C}$	1450	Α					
Freewheeling diode								
I <sub>F</sub>	$T_c = 25 (80)  ^{\circ}C$	230 (150)	Α					
I <sub>FRM</sub>	$t_p = 1 \text{ ms}$	400	Α					
I <sub>FSM</sub>	$t_p = 10 \text{ ms; sin; } T_j = 150 \text{ °C}$	2200	Α					

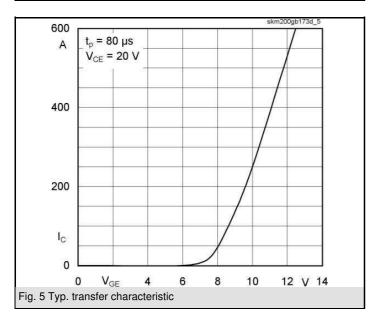
Characte	ristics	T <sub>c</sub> = 25 °C	T <sub>c</sub> = 25 °C, unless otherwise specified				
Symbol	Conditions	min.	typ.	max.	Units		
IGBT							
$V_{GE(th)}$ $I_{CES}$ $V_{CE(TO)}$ $r_{CE}$	$V_{GE} = V_{CE}$ , $I_{C} = 10 \text{ mA}$ $V_{GE} = 0$ , $V_{CE} = V_{CES}$ , $T_{j} = 25 (125) °C$ $T_{j} = 25 (125) °C$ $V_{GE} = 15 \text{ V}$ , $T_{j} = 25 (125) °C$	4,8	5,5 0,1 1,65 (1,9) 11,7 (17,3)	6,2 0,3 1,9 (2,15) 13,3 (19)	V mA V mΩ		
V <sub>CE(sat)</sub>	I <sub>Cnom</sub> = 150 A, V <sub>GE</sub> = 15 V, chip level		3,4 (4,5)	3,9 (5)	V		
C <sub>ies</sub> C <sub>oes</sub> C <sub>res</sub> L <sub>CE</sub> R <sub>CC'+EE'</sub>	under following conditions $V_{GE}$ = 0, $V_{CE}$ = 25 V, f = 1 MHz res., terminal-chip $T_c$ = 25 (125) °C		20 2 0,55 0,35 (0,5)	20	nF nF nF nH mΩ		
$\begin{aligned} & t_{d(on)} \\ & t_r \\ & t_{d(off)} \\ & t_f \\ & E_{on} \left( E_{off} \right) \end{aligned}$	$V_{CC} = 1200 \text{ V}, I_{Cnom} = 150 \text{ A}$ $R_{Gon} = R_{Goff} = 4 \Omega, T_j = 125 \text{ °C}$ $V_{GE} = \pm 15 \text{ V}$		580 100 750 40 95 (45)		ns ns ns ns mJ		
Inverse diode							
$V_F = V_{EC}$	$I_{Fnom}$ = 150 A; $V_{GE}$ = 0 V; $T_j$ = 25 (125)		2,2 (1,9)	2,7	V		
$V_{(TO)}$ $r_{T}$ $I_{RRM}$ $Q_{rr}$ $E_{rr}$	$T_j$ = 125 () °C $T_j$ = 125 () °C $I_{Fnom}$ = 150 A; $T_j$ = 25 ( 125 ) °C $di/dt$ = 1000 A/ $\mu$ s $V_{GE}$ = 0 V		1,3 4,5 60 (85) 15 (38)	1,5 6,2	V mΩ A μC mJ		
FWD							
$\begin{aligned} & V_{F} = V_{EC} \\ & V_{(TO)} \\ & \Gamma_{T} \\ & I_{RRM} \\ & Q_{rr} \\ & E_{rr} \end{aligned}$	$\begin{aligned} &   I_F = 150 \text{ A; } V_{GE} = 0 \text{ V, } T_j = 25 \text{ (125) °C} \\ & T_j = 125 \text{ () °C} \\ & T_j = 125 \text{ () °C} \\ & I_F = 150 \text{ A; } T_j = 25 \text{ (125 ) °C} \\ & \text{di/dt} = \text{A/}\mu\text{s} \\ & V_{GE} = \text{V} \end{aligned}$		2 (1,8) 1,3 3,5 75 (110) 20 (50)	2,4 1,5 4,5	V V mΩ A μC mJ		
	characteristics	ī					
$\begin{aligned} R_{th(j\text{-}c)} \\ R_{th(j\text{-}c)D} \\ R_{th(j\text{-}c)FD} \\ R_{th(c\text{-}s)} \end{aligned}$	per IGBT per Inverse Diode per FWD per module			0,1 0,32 0,21 0,038	K/W K/W K/W		
Mechanical data							
M <sub>s</sub> M <sub>t</sub>	to heatsink M6 to terminals M6	3		5	Nm Nm		
w				325	g		

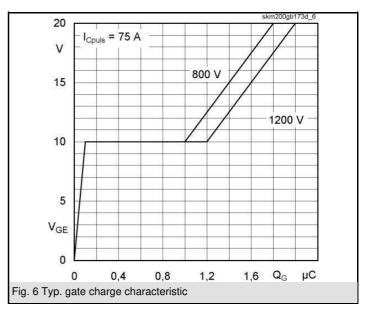


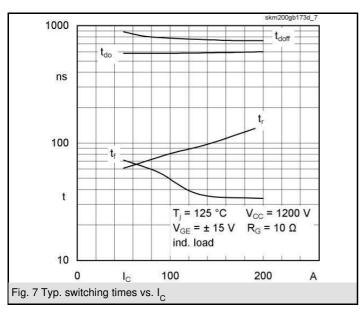


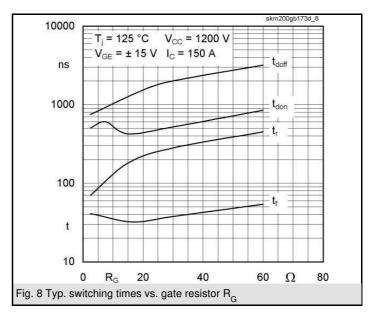


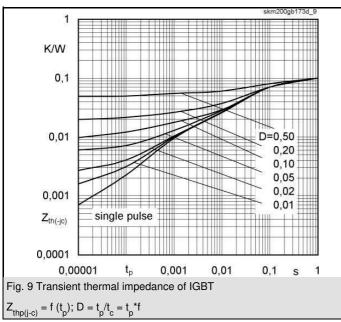


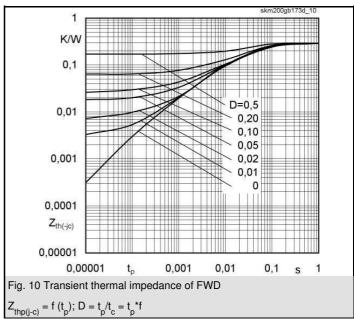


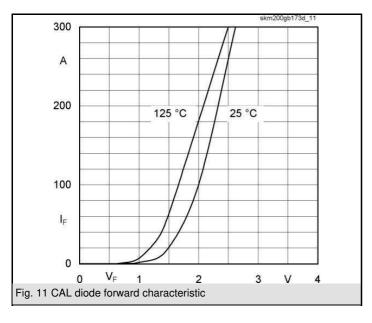


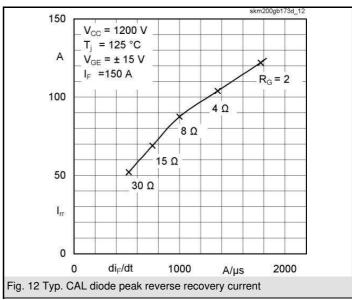


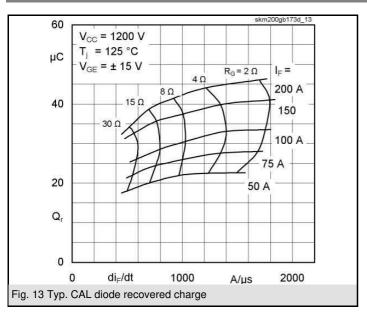


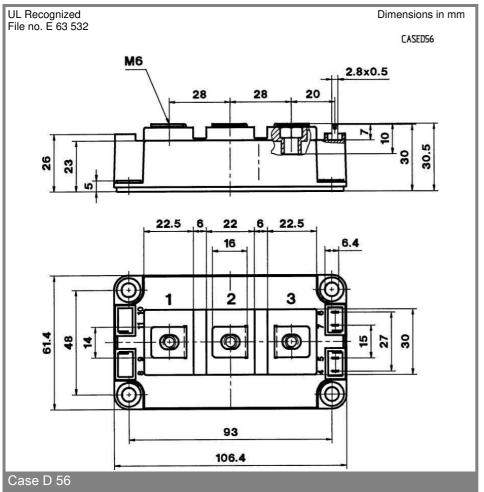


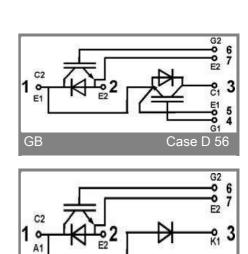


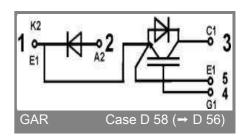












Case D 57 (→ D 56)

GAI

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

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